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U.S. Department of Commerce, Patent and Trademark Office							Docket No.		Serial No.	
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INFORMATION DISCLOSURE STATEMENT BY APPLICANT						Applicar	Applicant		Confirmation No.:	
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U.S. Department of Commerce, Patent and Trademark Office					Docket I	Docket No.			
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U.S. Department of Commerce, Patent and Trademark Office					Docket	Docket No.		Serial No.	
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